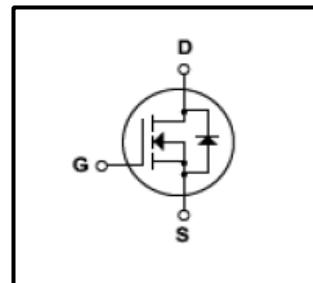
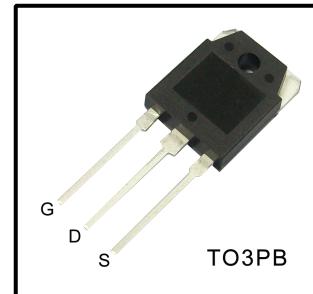


**Silicon N-Channel MOSFET**
**Features**

- 18A,500V, $R_{DS(on)}$ (Max0.27Ω)@ $V_{GS}=10V$
- Ultra-low Gate charge(Typical 42nC)
- Fast Switching Capability
- 100%Avalanche Tested
- Maximum Junction Temperature Range(150°C)


**General Description**

This Power MOSFET is produced using Winsemi's advanced planar stripe,VDMOS technology.this latest technology has been especially designed to minimize on-state resistance, have a high rugged avalanche characteristics .This devices is specially wells suited for AC-DC switching power supplies, DC-DC power Converters high voltage H-bridge motor drive PWM


**Absolute Maximum Ratings**

Symbol	Parameter	Value	Units
$V_{DSS}$	Drain Source Voltage	500	V
$I_D$	Continuous Drain Current(@ $T_c=25^\circ C$ )	18	A
	Continuous Drain Current(@ $T_c=100^\circ C$ )	12.7	A
$I_{DM}$	Drain Current Pulsed	(Note1)	A
$V_{GS}$	Gate to Source Voltage	$\pm 30$	V
$E_{AS}$	Single Pulsed Avalanche Energy	(Note2)	mJ
$E_{AR}$	Repetitive Avalanche Energy	(Note1)	mJ
$dv/dt$	Peak Diode Recovery $dv/dt$	(Note3)	V/ns
$P_D$	Total Power Dissipation(@ $T_c=25^\circ C$ )	208	W
$T_J$	Junction Temperature	150	°C
$T_{stg}$	Storage Temperature	-55~150	°C
$T_L$	Channel Temperature	300	°C

**Thermal Characteristics**

Symbol	Parameter	Value			Units
		Min	Typ	Max	
$R_{QJC}$	Thermal Resistance , Junction -to -Case	-	-	0.60	°C/W
$R_{QJA}$	Thermal Resistance , Junction-to -Ambient	-	-	40	°C/W

**Electrical Characteristics(Tc=25°C)**

Characteristics	Symbol	Test Condition	Min	Type	Max	Unit	
Gate leakage current	$I_{GSS}$	$V_{GS}=\pm 25V, V_{DS}=0V$	-	-	$\pm 10$	nA	
Gate-source breakdown voltage	$V_{(BR)GSS}$	$I_G=10 \mu A, V_{DS}=0V$	$\pm 30$	-	-	V	
Drain cut -off current	$I_{DSS}$	$V_{DS}=500V, V_{GS}=0V$	-	-	100	$\mu A$	
Drain -source breakdown voltage	$V_{(BR)DSS}$	$I_D=10 mA, V_{GS}=0V$	500	-	-	V	
Breakdown voltage Temperature coefficient	$\triangle BV_{DSS}/\triangle T_J$	$I_D=250\mu A$ , Referenced to 25°C	-	0.5	-	V/°C	
Gate threshold voltage	$V_{GS(th)}$	$V_{DS}=10V, I_D=1mA$	3	-	5	V	
Drain -source ON resistance	$R_{DS(ON)}$	$V_{GS}=10V, I_D=9A$	-	0.23	0.27	$\Omega$	
Forward Transconductance	$g_{fs}$	$V_{DS}=40V, I_D=9A$	-	16	-	S	
Input capacitance	$C_{iss}$	$V_{DS}=25V,$ $V_{GS}=0V,$ $f=1MHz$	-	2530	3290	pF	
Reverse transfer capacitance	$C_{rss}$		-	11	14.3		
Output capacitance	$C_{oss}$		-	300	390		
Switching time	Rise time	$t_r$	$V_{DD}=250V,$ $I_D=18A$ $R_G=25\Omega$ (Note4,5)	-	40	90	ns
	Turn-on time	$t_{on}$		-	150	310	
	Fall time	$t_f$		-	95	200	
	Turn-off time	$t_{off}$		-	110	230	
Total gate charge(gate-source plus gate-drain)	$Q_g$	$V_{DD}=400V,$ $V_{GS}=10V,$ $I_D=18A$ (Note4,5)	-	42	55	nC	
Gate-source charge	$Q_{gs}$		-	12	-		
Gate-drain("miller") Charge	$Q_{gd}$		-	14	-		

**Source-Drain Ratings and Characteristics(Ta=25°C)**

Characteristics	Symbol	Test Condition	Min	Type	Max	Unit
Continuous drain reverse current	$I_{DR}$	-	-	-	18	A
Pulse drain reverse current	$I_{DRP}$	-	-	-	72	A
Forward voltage(diode)	$V_{DSF}$	$I_{DR}=18A, V_{GS}=0V$	-	-	1.4	V
Reverse recovery time	$t_{rr}$	$I_{DR}=18A, V_{GS}=0V,$ $dI_{DR} / dt = 100 A / \mu s$	-	500	-	ns
Reverse recovery charge	$Q_{rr}$		-	5.4	-	$\mu C$

Note 1.Repeativity rating :pulse width limited by junction temperature

2.L=5.2mH  $I_{AS}=18A, V_{DD}=50V, R_G=25\Omega$ ,Starting  $T_J=25^\circ C$

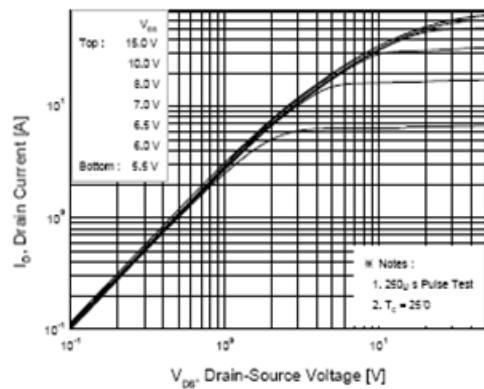
3. $I_{SD}\leq 18A, di/dt\leq 200A/\mu s, V_{DD}<BV_{DSS}$ ,STARTING  $T_J=25^\circ C$

4.Pulse Test:Pulse Width $\leq 300\mu s$ ,Duty Cycle $\leq 2\%$

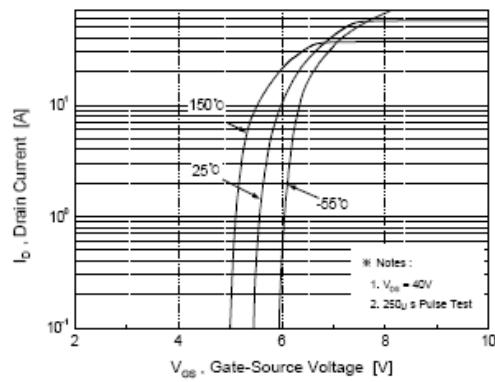
5. Essentially independent of operating temperature.

This transistor is an electrostatic sensitive device

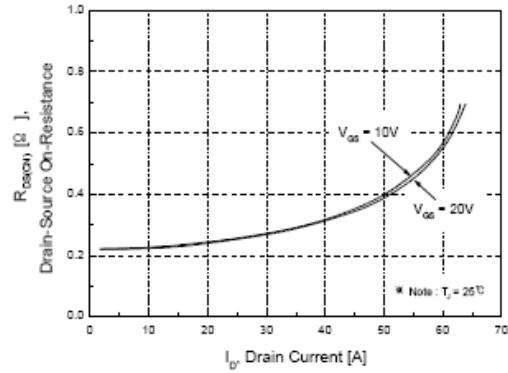
Please handle with caution



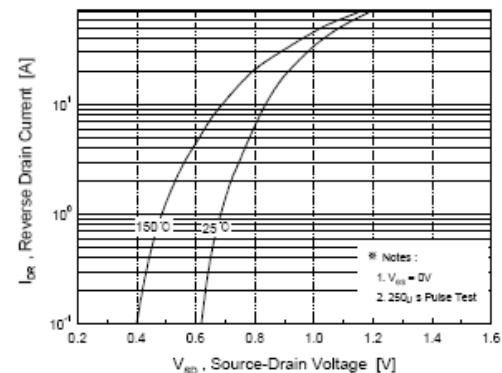
**Fig.1 On State Characteristics**



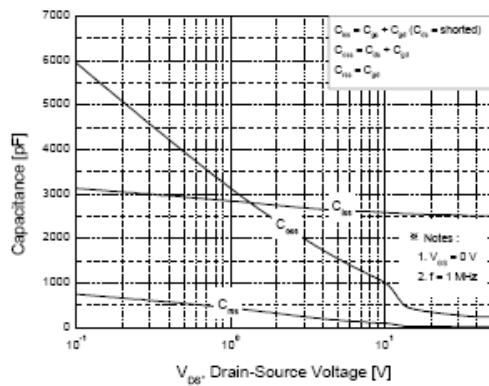
**Fig.2 Transfer Current Characteristics**



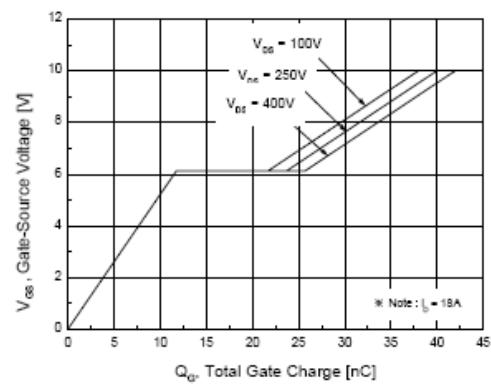
**Fig.3 On-Resistance Variation vs Drain Current**



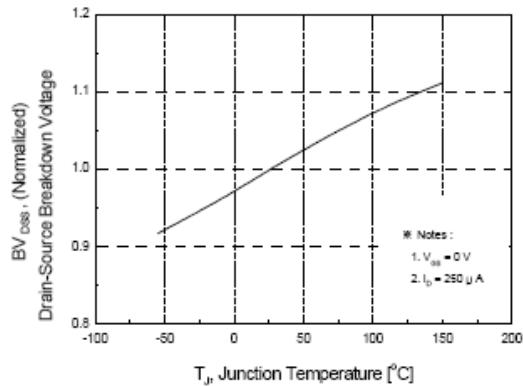
**Fig.4 Body Diode Forward Voltage Variation with Source Current and Temperature**



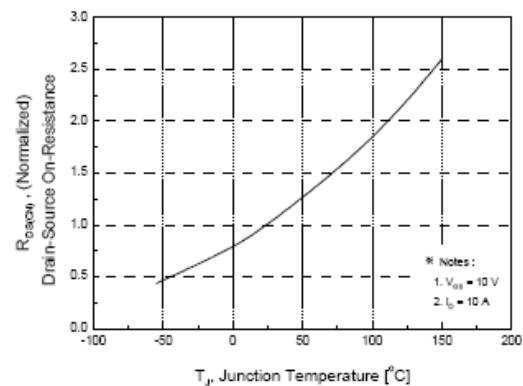
**Fig.5 Capacitance Characteristics**



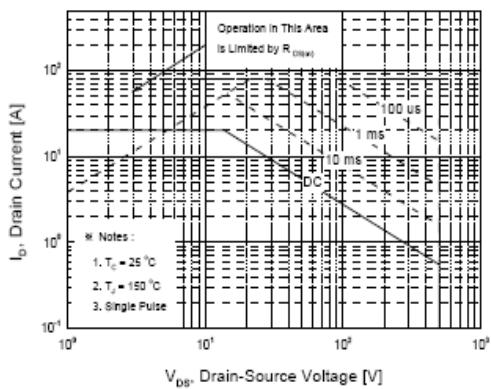
**Fig.6 Gate Charge Characteristics**



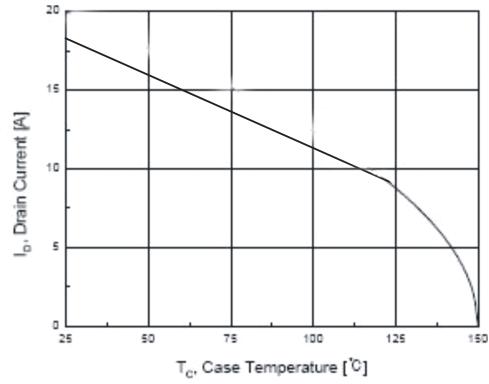
**Fig.7 Breakdown Voltage Variation**



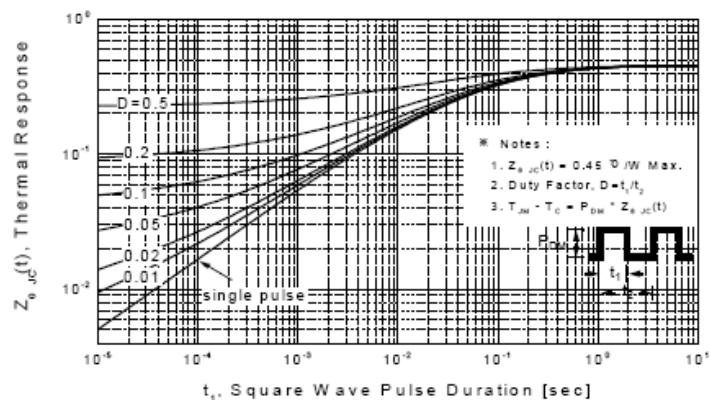
**Fig.8 On-Resistance Variation  
vs.Temperature**



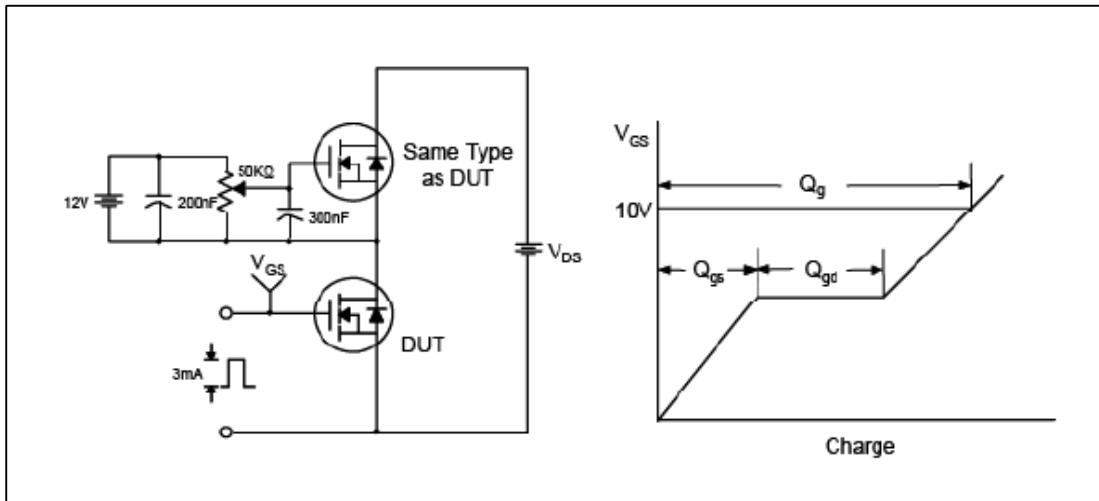
**Fig.9 Maximum Safe Operation Area**



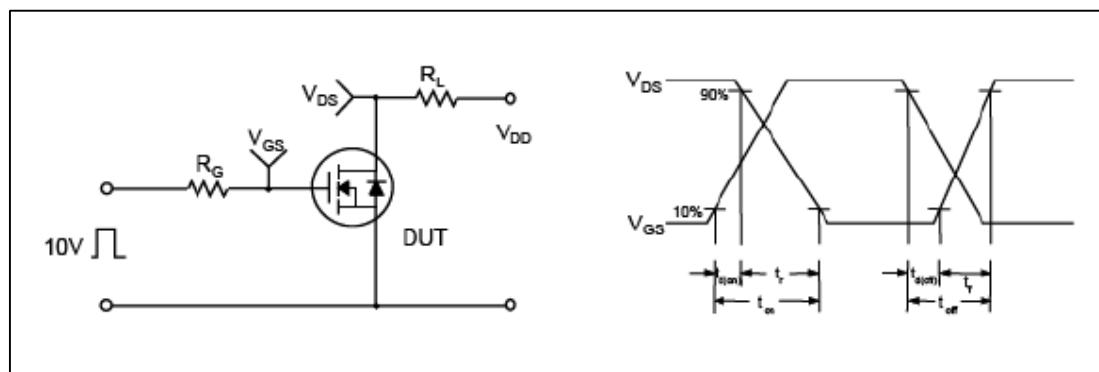
**Fig.10 Maximum Drain Current vs  
Case Temperature**



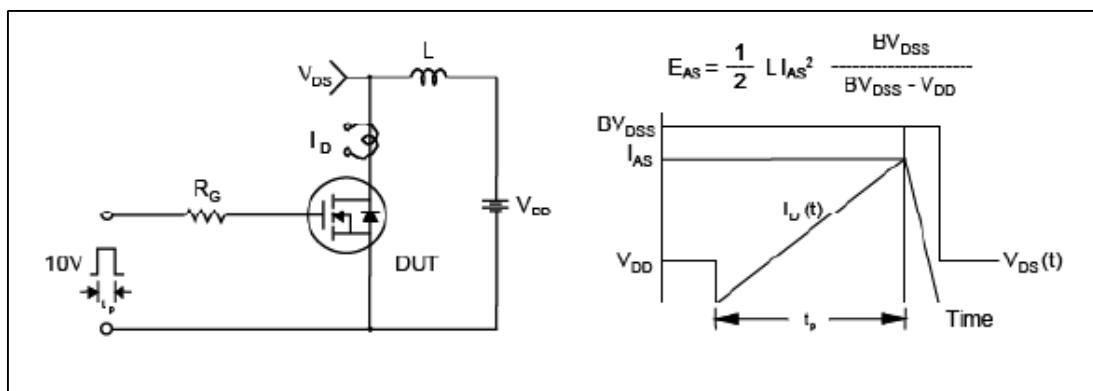
**Fig.11 Transient Thermal Response Curve**



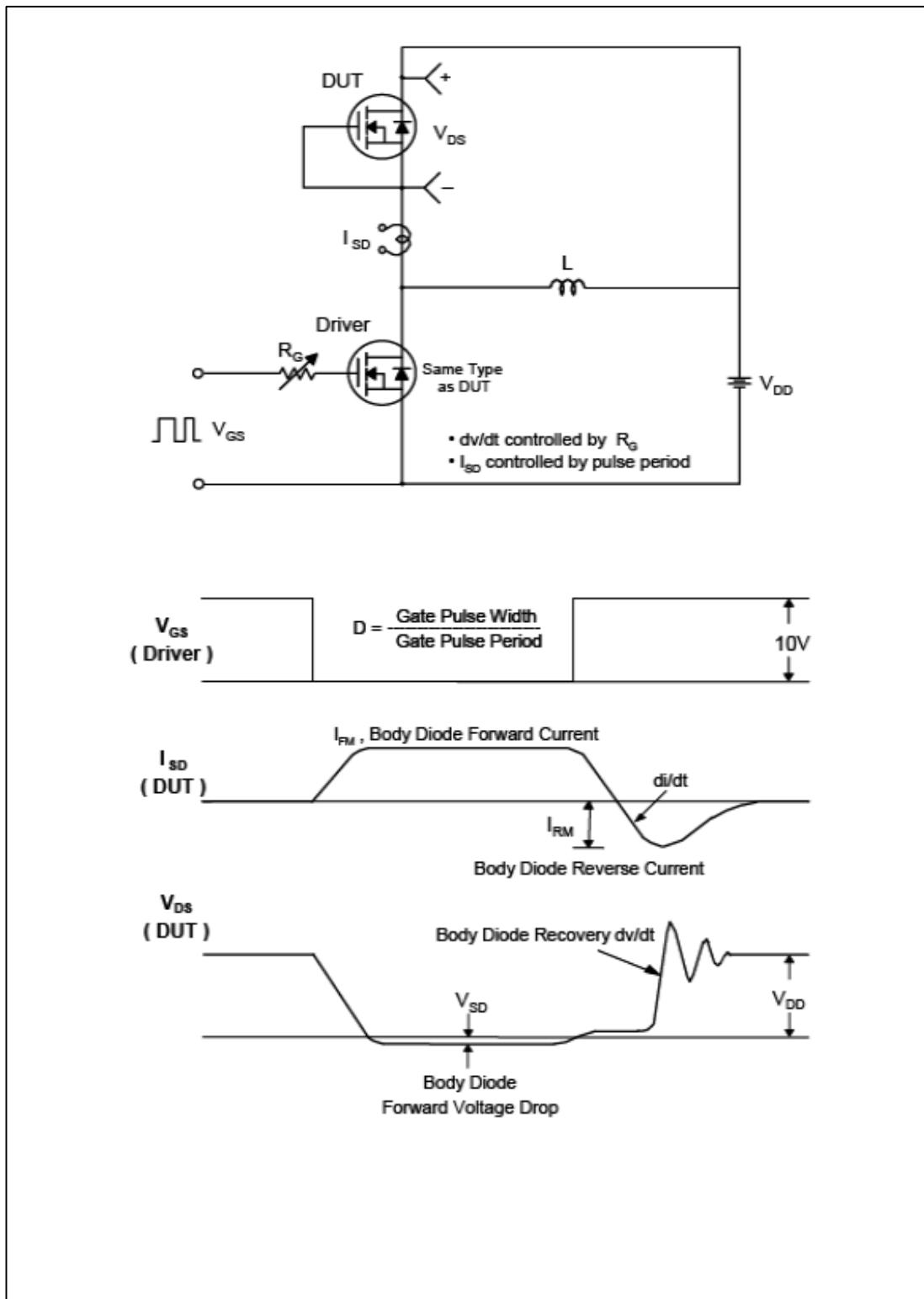
**Fig.12 Gate Test Circuit & Waveform**



**Fig.13 Resistive Switching Test Circuit & Waveform**



**Fig.14 Unclamped Inductive Switching Test Circuit & Waveform**



**Fig.15 Peak Diode Recovery  $dv/dt$  Test Circuit & Waveform**

**TO-3PB Package Dimension**

